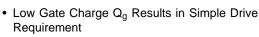


SSD2N60S5-VB Datasheet N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	650				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V 4				
Q _g (Max.) (nC)	11				
Q _{gs} (nC)	2.3				
Q _{gd} (nC)	5.2				
Configuration	Single				

FEATURES

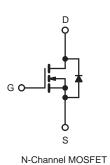




• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650	V	
Gate-Source Voltage			V_{GS}	± 30	7 v	
Continuous Drain Currente	V _{GS} at 10 V	T _C = 25 °C	1	2.0		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	1.28	Α	
Pulsed Drain Current ^a			I _{DM}	8		
Linear Derating Factor				0.48	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	165	mJ	
Repetitive Avalanche Current ^a			I _{AR}	2	Α	
Repetitive Avalanche Energy ^a			E _{AR}	6	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	45	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) ^d for 10 s				300		
Mounting Torque		A2 corow		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω , I_{AS} = 3.2 A (see fig. 12).
- c. $I_{SD} \le 3.2$ A, $dI/dt \le 90$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.1	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA ^d	-	670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 30 V	ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 650 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1 A b	-	4.0	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D = 1 A	3.9	-	-	S
Dynamic		1					1
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	417	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	45	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	5	-	
Output Capacitance	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	ı	912	-	pF
Output Capacitance		$V_{GS} = 0 V$	V _{DS} = 520 V, f = 1.0 MHz	ı	26		
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 520 V ^c		42	-	
Total Gate Charge	Q_g			-	-	11	
Gate-Source Charge	Q_gs	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 1.2 \text{ A}, V_{DS} = 400 \text{ V}$ see fig. 6 and 13 ^b		-	2.3	nC
Gate-Drain Charge	Q_{gd}				-	5.2	
Turn-On Delay Time	t _{d(on)}		1		14	-	
Rise Time	t _r		= 325 V, I _D = 1.2A	i	20	-	
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$	$R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. 10^b		34	-	ns -
Fall Time	t _f	j		-	18	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	8	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 3.2 A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T. = 25 °C L	T 25 00 1 2 2 A 21/24 400 A / 22h		180	230	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 3.2 \text{A}, dI/dt = 100 \text{A/}\mu\text{s}^{\text{b}}$		-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %. c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

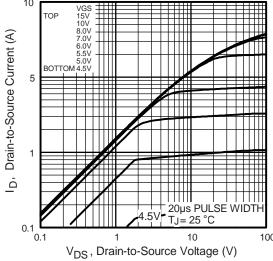
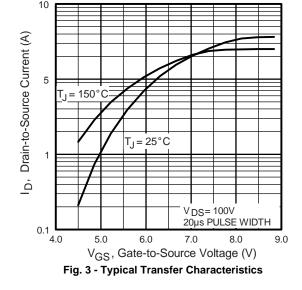


Fig. 1 - Typical Output Characteristics



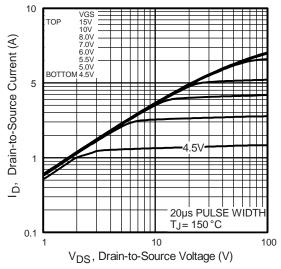


Fig. 2 - Typical Output Characteristics

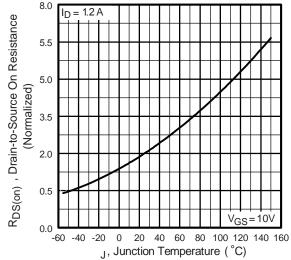


Fig. 4 - Normalized On-Resistance vs. Temperature



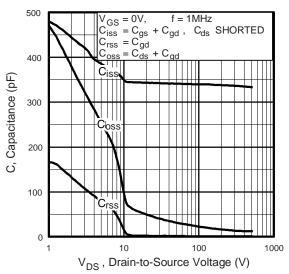


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

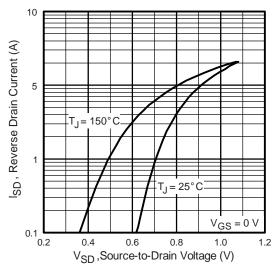


Fig. 7 - Typical Source-Drain Diode Forward Voltage

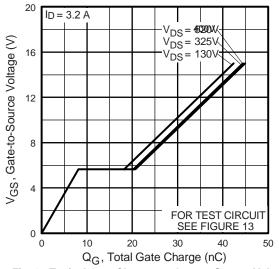


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

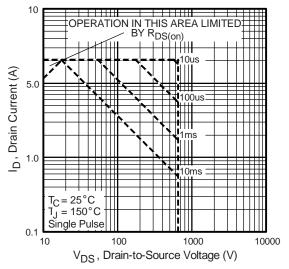


Fig. 8 - Maximum Safe Operating Area



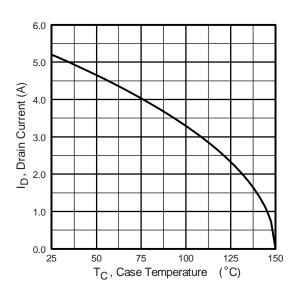


Fig. 9 - Maximum Drain Current vs. Case Temperature

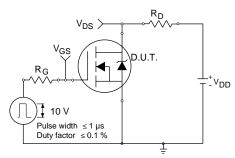


Fig. 10a - Switching Time Test Circuit

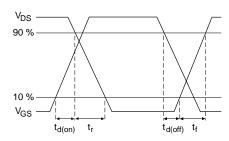


Fig. 10b - Switching Time Waveforms

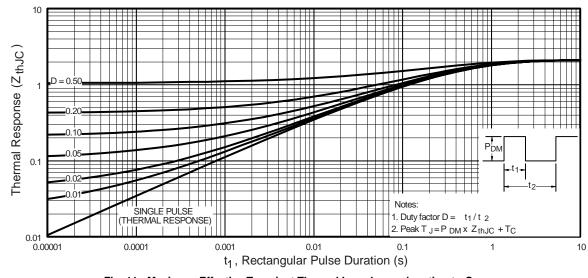


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

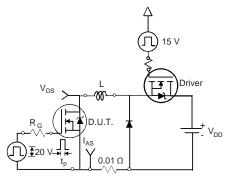


Fig. 12a - Unclamped Inductive Test Circuit

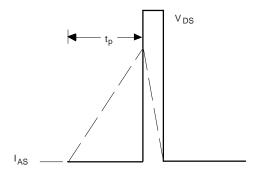


Fig. 12b - Unclamped Inductive Waveforms



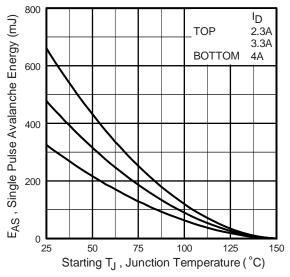


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

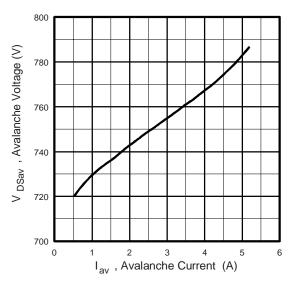


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

6

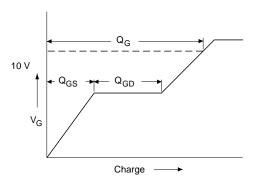


Fig. 13a - Basic Gate Charge Waveform

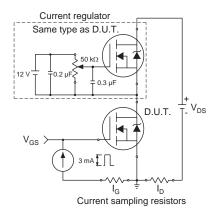
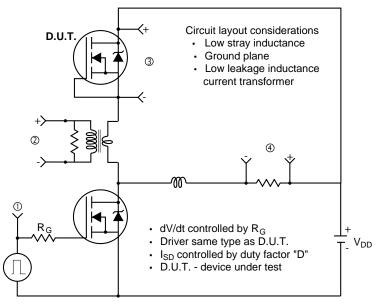


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



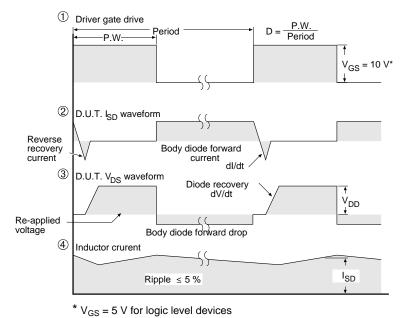
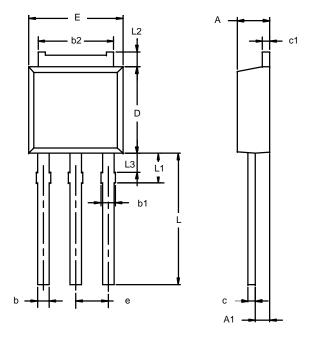


Fig. 14 - For N-Channel



TO-251AA



Note: D	Dimension I	L3 is for	reference	only.
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	MILLIM	IETERS	INCHES		
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090	BSC	
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	



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